

<b>Notice of References Cited</b>	Application/Control No. ✓ 10/027,462	Applicant(s)/Patent Under Reexamination YAROSLAVSKY ET AL.	
	Examiner Manav Seth	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,789,898	12-1988	Zwirn et al.	348/354
*	B	US-6,067,164	05-2000	Onoguchi et al.	356/401
*	C	US-3,918,071	11-1975	Albrecht, Fritz	396/101
*	D	US-4,404,594	09-1983	Hannan, William J.	348/355
*	E	US-4,825,065	04-1989	Imai, Ryoichi	250/205
*	F	US-4,816,919	03-1989	Coates, Philip V.	348/353
*	G	US-5,534,924	07-1996	Florant, Olivier	348/364
*	H	US-3,878,323	04-1975	Fisher, Colin	348/573
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Rooks et al., IEEE, June 5 1999, "Development of an inspection process for ball-grid-array technology using scanned-beam X-ray laminography". (pp. 851-861)
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.